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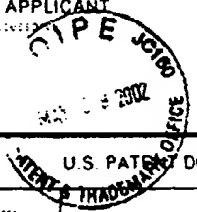
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Sheet 1 of 1

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1657		SERIAL NO. 09 905.320	
LIST OF ART CITED BY APPLICANT <small>(Use several sheets if needed)</small>				APPLICANT: Cam Basceri et al			
				FILING DATE July 13, 2001		GROUP 1762	



U.S. PATENT DOCUMENTS

Examiner's Mark	Document Number	Date	Country	Class	Subclass	Filing Date by Applicant
EF						

FOREIGN PATENT DOCUMENTS

Document Number	Date	Country	Class	Subclass	Translation	
					Yes	No

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

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EXAMINER <i>E. Falt</i>	DATE CONSIDERED 9/4/02
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*EXAMINER Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

8/29/01

Form 1-99

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. 0022 1667	SERIAL NO. 0022 1667
LIST OF ART CITED BY APPLICANT <small>(To be filled in by the applicant)</small>		APPLICANT (Name, Address, etc.)	
FILING DATE 8/29/01		GROUP 1	

U.S. PATENT DOCUMENTS							
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FOREIGN PATENT DOCUMENTS							
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
<div style="font-size: 2em; font-weight: bold;">CF</div>	AR		Kim, et al. Structural and Electrical Properties of RuTe ₂ grown on p-InP (100) by low pressure metalorganic chemical vapor deposition at low temperature. Applied Physics Letters, U.S. American Institute of Physics Vol. 65, No. 15, 10/10/94, Pgs. 1955-1957
	AS		
	AT		

EXAMINER <div style="font-family: cursive; font-size: 1.2em;">E. J. ...</div>	DATE CONSIDERED <div style="font-family: cursive; font-size: 1.2em;">12/6/01</div>
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EXAMINER: Initial or reference considered, whether or not contained in a reference with MPEP 609. Draw the through citation if not in a reference and not considered. Include a note if the form with best construction is to be applied.

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U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ACTY. DOCKET NO. 0022-167		SERIAL NO. 000004220	
		APPLICANT Gen Research, Inc.			
LIST OF ART CITED BY APPLICANT <small>(See serial sheets if necessary)</small>		FILING DATE Feb. 15, 2001		GRS # 10000000	

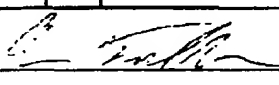
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
EF	AR		Takashi Kawahara et al., (Ba, SrTiO ₃) Films Prepared by Liquid Source Chemical Vapor Deposition on Ru Electrodes, 35 Jpn. J. Appl. Phys. Pt. 1, No. 9B, pp. 4850, 4853 (1996).
CF	AS		Rajesh Khemwani et al., A Novel Low-Temperature Process for High Dielectric Constant BST Thin Films for 1T1M DRAM Applications, Motorola Research Center, Austin, TX (Undated), 2 pages.
CF	AT		Yong Tae Kim et al., Abstract, Advantages of Ru ₂ O ₃ bottom electrode in the dielectric and leakage characteristics of (Ba, Sr)TiO ₃ capacitor, 35 Jpn. J. Appl. Phys. Pt. 1, No. 12A, pp. 6153-6156 (1996).

EXAMINER 	DATE CONSIDERED 12/05/01
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*EXAMINER: Ined if reference considered, whether or not citation is in accordance with MPEP (90). Draw line through citation if not in accordance and not considered. Include a copy of this form with next communication from applicant.

Form PTO/US-101		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		APP. TRACKING NO. M22 2687		SERIAL NO. 60064326	
LIST OF ART CITED BY APPLICANT <small>(Use separate sheets if necessary)</small>				APPLICANT Gen. Electric Co.			
				FILING DATE Jan. 23, 2002		CLASS. DATE Jan. 23, 2002	
U.S. PATENT DOCUMENTS							
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	AN						
	AO						
	AP						
OTHER REFERENCES (including Author, Title, Date, Portion, Pages, Etc.)							
EF	AR	SH. Park et al. Abstract, Characterization of MIS exposure of BSI thin films deposited on Si by RF magnetron sputtering					
		Technology, Hyn Electronics, San Francisco, CA, pp. 33-39, April 7, 1998.					
EF	AS	N. Takeuchi et al. Abstract, Effect of truing atmosphere on the color hue and gloss of BSI, No. 100, 98-2000					
		SIKAMURA, KIKUO; GAKO, RITSU; ROBINSON, N. C., pp. 530-539 (1999)					
EF	AT	H. Yamashita et al. Abstract, Resective exposure method and characterization of SiO ₂ thin films, BELL					
		International Symposium on Applications of Technology, October 21, 1997, pp. 25-28, August 2, 1997					
EXAMINER					DATE CONSIDERED		
					12/15/01		
EXAMINER: Initial of reference considered whether or not citation is in continuance with MPEP 609. If not, then cite separately in not in continuance and not a related. Include copy of citation with next communication to applicant.							

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

LIST OF ART CITED BY APPLICANT
(For official use only - necessary)

ATTY. DOCKET NO.
M22-057

SERIAL NO.
06/001320

APR 25 2001

APPLICANT
Light Research, Inc.

FILING DATE
JUN 22, 2000

CLASS
G06F

U.S. PATENT DOCUMENTS

Sequence Number	Doc. Number	Date	Name	Class	Subclass	Filing Date
1	AA 5,296,443	10/26/93	Nakamura			
2	AB 5,731,944	01/21/97	Endo			
3	AC 5,776,294	03/24/94	Yabuta et al.			
4	AD 5,743,203	01/10/98	Yusuf et al.			
5	AE 5,798,616	07/21/98	Roh			
6	AF 6,643,320	09/25/98	Blair et al.			
7	AG 6,346,349	02/26/00	Okuma			
8	AH 6,078,402	04/03/00	Kakutani et al.			
9	AI 6,253,815	06/20/00	Hama et al.			
10	AJ 6,037,296	11/28/00	Watanabe			
11	AK 6,077,203	03/14/01	Hibi et al.			

FOREIGN PATENT DOCUMENTS

Sequence Number	Doc. Number	Date	Country	Class	Subclass	Translation	
						Yes	No
12	AL 0,355,774-A2	26/01/98	EPO - Philips et al. Applied Materials, Inc.				
13	AM 0,357,332-A2	12/05/99	EPO - Fuda, Makoto; Mitsubishi Electric Ind. Co.				
14	AN WO 98/09497	20/02/98	WIPO - Simpson, John et al.				
15	AO 0,474,140-A1	30/08/01	EPO - Kamigaito, Satoshi et al. NEC Corporation				
16	AP WO 98/06465	11/06/99	WIPO - Narwakar et al. Applied Materials, Inc.				

OTHER REFERENCES (including Author, Title, Date, Page(s), etc.)

17	AR	Steve Bishara et al., <i>Composition Dependence of the Defective Properties of MOCVD GaN</i> , pp. 1-21 (MRS Lab Meeting 12/01/94).
		Steve M. Bishara et al., <i>MOCVD GaN for High Density DRAM Applications</i> (Report for SEMATECH/WEST 07/12/95) 2 page.
18	AI	Y. C. Chen et al., <i>Abstract, Improvements in the Properties of Chemical Vapor-Deposited GaN Grown Through Use of a Seed Layer</i> , 6 J. APPL. PHYS. Pt. 1, No. 12, pp. 6624-6628 (1997).

EXAMINER

DATE CONSIDERED

EXAMINER: Initial is retention is considered, whether or not written in accordance with MPEP 609. If a law through a retention is not in a form and not a retention. The date of this form with the retention is not a retention.

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		APPY. DOCKET NO. M22 1657		SERIAL NO. 16,905,150			
LIST OF ART CITED BY APPLICANT <small>(For use in Part I, Section 2)</small>				APPLICANT <small>(See Basic Information)</small>			
FILING DATE 12/15/2001				CLASS 1-4, 16			
U.S. PATENT DOCUMENTS							
Examiner's Initials	Doc. No.	Date	Title	Class	Filing Date If Applicable		
EF	5,475,396	11/28/95	Moskwa et al.				
EF	5,254,806	10/10/93	Kanagawa				
EF	6,156,035	12/18/99	Agarwal et al.				
EF	6,165,334	12/18/99	Agarwal et al.				
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OTHER REFERENCES (including Author, Title, Date, Publication Pages, Etc.)							
EF	AP		Chong Ming Chu et al., Abstract, <i>Electronic properties and crystal structure of the SrTiO₃ films prepared at low temperatures</i>				
			in a LaNiO ₃ electrode by radio frequency magnetron sputtering, 70 APPLIED PHYSICS LETTERS No. 2, pp. 249-251 (1997)				
EF	AI		Kazuhito Iyama et al., Abstract, <i>Chemical vapor deposition on the SrTiO₃ thin films on application in organic LEDs</i>				
			dynamic random access memories, 14 INTEGRATED CIRCUITS No. 1-3, Pt. 1, pp. 33-42, 1997				
EF	AI		QIN, Jie et al., Abstract, <i>Structural and electronic properties of Bi₂Se₃ thin films with an epitaxial bottom electrode</i>				
			INTEGRATED CIRCUITS No. 1-4, pp. 111-119, 1998				
EXAMINER			DATE CONSIDERED				
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<small>*EXAMINER: Please refer to the enclosed, whether it is citation is in accordance with MPEP 609. Draw line through citation if not in accordance and so considered. Include a note of this in the Remarks section of the application.</small>							

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1657		SERIAL NO. 09/905.320	
LIST OF ART CITED BY APPLICANT <small>(Use several sheets if necessary)</small>				APPLICANT: Cem Basceri et al.			
				FILING DATE July 13, 2001		GROUP 1782	
U.S. PATENT DOCUMENTS							
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EF	AA	5/5/91, 2/94	5/5/91	357	200		
	AB						
EF	AC	02/24/98	Agreed in st. (filed) and amended in response to 05/29/98 Office Action, 11/20/98 Office Action, and 11/20/98 Office Action.			August 28, 1998	
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			9/30/02				
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 608; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							

1994, 1995, 1996, 1997, 1998, 1999, 2000, 2001, 2002, 2003, 2004, 2005, 2006, 2007, 2008, 2009, 2010, 2011, 2012, 2013, 2014, 2015, 2016, 2017, 2018, 2019, 2020, 2021, 2022, 2023, 2024, 2025, 2026, 2027, 2028, 2029, 2030, 2031, 2032, 2033, 2034, 2035, 2036, 2037, 2038, 2039, 2040, 2041, 2042, 2043, 2044, 2045, 2046, 2047, 2048, 2049, 2050, 2051, 2052, 2053, 2054, 2055, 2056, 2057, 2058, 2059, 2060, 2061, 2062, 2063, 2064, 2065, 2066, 2067, 2068, 2069, 2070, 2071, 2072, 2073, 2074, 2075, 2076, 2077, 2078, 2079, 2080, 2081, 2082, 2083, 2084, 2085, 2086, 2087, 2088, 2089, 2090, 2091, 2092, 2093, 2094, 2095, 2096, 2097, 2098, 2099, 2100, 2101, 2102, 2103, 2104, 2105, 2106, 2107, 2108, 2109, 2110, 2111, 2112, 2113, 2114, 2115, 2116, 2117, 2118, 2119, 2120, 2121, 2122, 2123, 2124, 2125, 2126, 2127, 2128, 2129, 2130, 2131, 2132, 2133, 2134, 2135, 2136, 2137, 2138, 2139, 2140, 2141, 2142, 2143, 2144, 2145, 2146, 2147, 2148, 2149, 2150, 2151, 2152, 2153, 2154, 2155, 2156, 2157, 2158, 2159, 2160, 2161, 2162, 2163, 2164, 2165, 2166, 2167, 2168, 2169, 2170, 2171, 2172, 2173, 2174, 2175, 2176, 2177, 2178, 2179, 2180, 2181, 2182, 2183, 2184, 2185, 2186, 2187, 2188, 2189, 2190, 2191, 2192, 2193, 2194, 2195, 2196, 2197, 2198, 2199, 2200, 2201, 2202, 2203, 2204, 2205, 2206, 2207, 2208, 2209, 2210, 2211, 2212, 2213, 2214, 2215, 2216, 2217, 2218, 2219, 2220, 2221, 2222, 2223, 2224, 2225, 2226, 2227, 2228, 2229, 2230, 2231, 2232, 2233, 2234, 2235, 2236, 2237, 2238, 2239, 2240, 2241, 2242, 2243, 2244, 2245, 2246, 2247, 2248, 2249, 2250, 2251, 2252, 2253, 2254, 2255, 2256, 2257, 2258, 2259, 2260, 2261, 2262, 2263, 2264, 2265, 2266, 2267, 2268, 2269, 2270, 2271, 2272, 2273, 2274, 2275, 2276, 2277, 2278, 2279, 2280, 2281, 2282, 2283, 2284, 2285, 2286, 2287, 2288, 2289, 2290, 2291, 2292, 2293, 2294, 2295, 2296, 2297, 2298, 2299, 2300, 2301, 2302, 2303, 2304, 2305, 2306, 2307, 2308, 2309, 2310, 2311, 2312, 2313, 2314, 2315, 2316, 2317, 2318, 2319, 2320, 2321, 2322, 2323, 2324, 2325, 2326, 2327, 2328, 2329, 2330, 2331, 2332, 2333, 2334, 2335, 2336, 2337, 2338, 2339, 2340, 2341, 2342, 2343, 2344, 2345, 2346, 2347, 2348, 2349, 2350, 2351, 2352, 2353, 2354, 2355, 2356, 2357, 2358, 2359, 2360, 2361, 2362, 2363, 2364, 2365, 2366, 2367, 2368, 2369, 2370, 2371, 2372, 2373, 2374, 2375, 2376, 2377, 2378, 2379, 2380, 2381, 2382, 2383, 2384, 2385, 2386, 2387, 2388, 2389, 2390, 2391, 2392, 2393, 2394, 2395, 2396, 2397, 2398, 2399, 2400, 2401, 2402, 2403, 2404, 2405, 2406, 2407, 2408, 2409, 2410, 2411, 2412, 2413, 2414, 2415, 2416, 2417, 2418, 2419, 2420, 2421, 2422, 2423, 2424, 2425, 2426, 2427, 2428, 2429, 2430, 2431, 2432, 2433, 2434, 2435, 2436, 2437, 2438, 2439, 2440, 2441, 2442, 2443, 2444, 2445, 2446, 2447, 2448, 2449, 2450, 2451, 2452, 2453, 2454, 2455, 2456, 2457, 2458, 2459, 2460, 2461, 2462, 2463, 2464, 2465, 2466, 2467, 2468, 2469, 2470, 2471, 2472, 2473, 2474, 2475, 2476, 2477, 2478, 2479, 2480, 2481, 2482, 2483, 2484, 2485, 2486, 2487, 2488, 2489, 2490, 2491, 2492, 2493, 2494, 2495, 2496, 2497, 2498, 2499, 2500, 2501, 2502, 2503, 2504, 2505, 2506, 2507, 2508, 2509, 2510, 2511, 2512, 2513, 2514, 2515, 2516, 2517, 2518, 2519, 2520, 2521, 2522, 2523, 2524, 2525, 2526, 2527, 2528, 2529, 2530, 2531, 2532, 2533, 2534, 2535, 2536, 2537, 2538, 2539, 2540, 2541, 2542, 2543, 2544, 2545, 2546, 2547, 2548, 2549, 2550, 2551, 2552, 2553, 2554, 2555, 2556, 2557, 2558, 2559, 2560, 2561, 2562, 2563, 2564, 2565, 2566, 2567, 2568, 2569, 2570, 2571, 2572, 2573, 2574, 2575, 2576, 2577, 2578, 2579, 2580, 2581, 2582, 2583, 2584, 2585, 2586, 2587, 2588, 2589, 2590, 2591, 2592, 2593, 2594, 2595, 2596, 2597, 2598, 2599, 2600, 2601, 2602, 2603, 2604, 2605, 2606, 2607, 2608, 2609, 2610, 2611, 2612, 2613, 2614, 2615, 2616, 2617, 2618, 2619, 2620, 2621, 2622, 2623, 2624, 2625, 2626, 2627, 2628, 2629, 2630, 2631, 2632, 2633, 2634, 2635, 2636, 2637, 2638, 2639, 2640, 2641, 2642, 2643, 2644, 2645, 2646, 2647, 2648, 2649, 2650, 2651, 2652, 2653, 2654, 2655, 2656, 2657, 2658, 2659, 2660, 2661, 2662, 2663, 2664, 2665, 2666, 2667, 2668, 2669, 2670, 2671, 2672, 2673, 2674, 2675, 26

UNITED STATES PATENT AND TRADEMARK OFFICE				PATENT APPLICATION		EXAMINER'S REPORT	
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No.	Ref.	Description	Date	Class	Status	Priority	Remarks
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